

Description

The AP12N10Y uses advanced trench technology to provide excellent $R_{\text{DS}(\text{ON})}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 100V I_{D} = 12A$

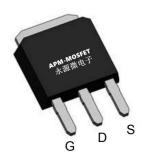
 $R_{DS(ON)}$ < 140m Ω @ V_{GS} =10V (Type: 110m Ω)

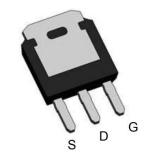


LED lighting

Load switch

Atomizer





Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP12N10Y	TO-251-3L	AP12N10Y XXX YYYY	4000

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Value	Unit		
VDS	Drain source voltage	Drain source voltage 100			
VGS	Gate source voltage	±20	V		
ID	Continuous drain current ¹⁾ , T _C =25 °C	12	А		
IDM	Pulsed drain current ²⁾ , T _C =25 ℃ 24		А		
P _D	Power dissipation ³⁾ , T _C =25 °C	17	W		
EAS	Single pulsed avalanche energy ⁵⁾ 1.2		mJ		
Tstg, Tj	Operation and storage temperature -55 to 150		℃		
RθJC	Thermal resistance, junction-case	7.4	°C/W		
RθJA	Thermal resistance, junction-ambient ⁴⁾	62	°C/W		





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
BVDSS	Drain-source breakdown voltage	V _{GS} =0 V, I _D =250 μA	100			V
VGS(th)	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250 μA	1.2 1.5		2.5	V
RDS(ON)	Drain-source on-state resistance	V _{GS} =10 V, I _D =5 A) V, I _D =5 A 110		140	mΩ
RDS(ON)	Drain-source on-state resistance	V _{GS} =4.5 V, I _D =3 A		160	180	mΩ
IGSS	Gate-source leakage current	V _{GS} =20 V			100	
1033	Gate-source leakage current	V _{GS} =-20 V			-100	- nA
IDSS	Drain-source leakage current	V _{DS} =100 V, V _{GS} =0 V			1	uA
Ciss	Input capacitance			206.1		pF
Coss	Output capacitance	$V_{GS}=0 \text{ V}, V_{DS}=50 \text{ V},$ f=100 kHz		28.9		pF
Crss	Reverse transfer capacitance	J 100 M 12		1.4		pF
td(on)	Turn-on delay time			14.7		ns
t _r	Rise time	V _{GS} =10 V, V _{DS} =50 V,		3.5		ns
td(off)	Turn-off delay time			20.9		ns
t _f	Fall time			2.7		ns
Q_g	Total gate charge			4.3		nC
Q _{gs}	Gate-source charge I _D =5 A,			1.5		nC
Q _{gd}	Gate-drain charge	V _{DS} =50 V, V _{GS} =10 V		1.1		nC
Vplateau	Gate plateau voltage			5.0		V
Is	Diode forward current	\(\(\O \) \(\(\) \(\) \(\)			7	
ISP	Pulsed source current	VGS <vth< td=""><td></td><td></td><td>21</td><td>A</td></vth<>			21	A
VSD	Diode forward voltage	I _S =7 A, V _{GS} =0 V			1.0	V
t _{rr}	Reverse recovery time			32.1		ns
Q _{rr}	Reverse recovery charge	I _S =5 A, di/dt=100 A/μs		39.4		nC
Irrm	Peak reverse recovery current			2.1		Α

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- $2\$ The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The test condition is V \leq 300us , duty cycle VDD=50 V, RG=25 Ω , L=0.1 mH, starting Tj=25 °C.
- 4. The power dissipation is limited by 150 $\!\!\!^{\circ}\!\!\!^{\circ}$ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

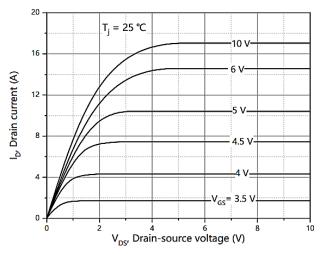


Figure 1. Typ. output characteristics

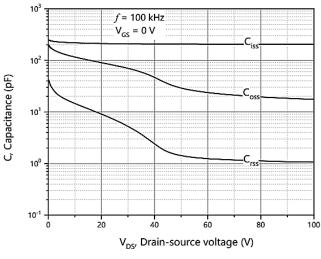


Figure 3. Typ. capacitances

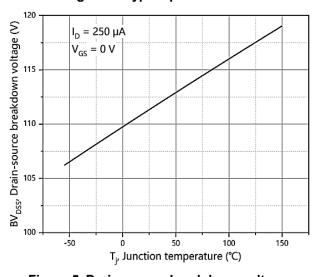


Figure 5. Drain-source breakdown voltage

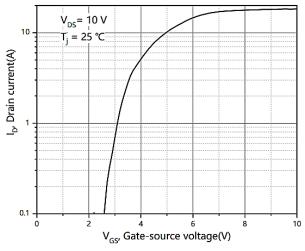


Figure 2. Typ. transfer characteristics

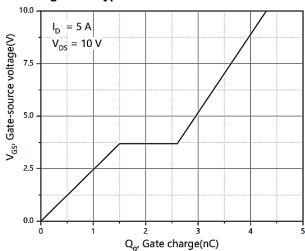


Figure 4. Typ. gate charge

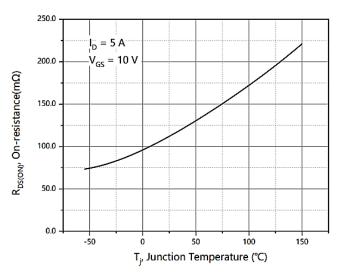
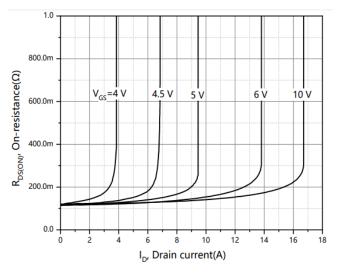


Figure 6. Drain-source on-state resistance







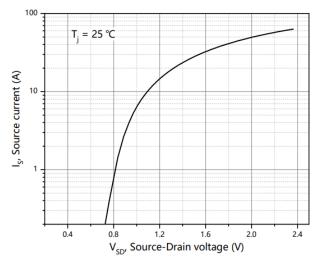
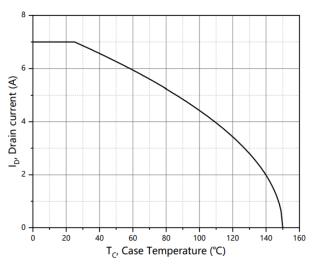


Figure 7. Drain-source on-state resistance

Figure 8. Forward characteristic of body diode



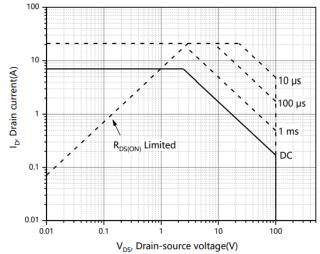
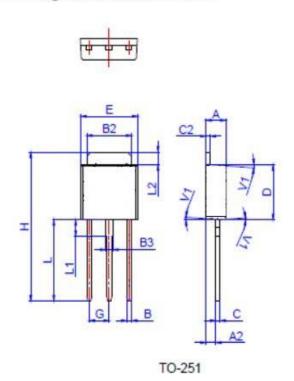


Figure 9. Drain current

Figure 10. Safe operation area T_C=25 ℃



Package Mechanical Data



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.20	(A)	2.40	0.086		0.095
A2	0.90		1.20	0.035		0.047
В	0.55		0.65	0.022		0.026
B2	5.10	3	5.40	0.200		0.213
В3	0.76		0.85	0.030		0.033
С	0.45		0.62	0.018		0.024
C2	0.48		0.62	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40	2	6.70	0.252		0.264
G		2.30			0.091	
н	16.0		17.0	0.630		0.669
L	8.90		9.40	0.350		0.370
L1	1.80		1.90	0.071		0.075
L2	1.37		1.50	0.054		0.059
V1		4°			4°	

Package Information -TO-251

OUTLINE	TUBE	INNER BOX	PER CARTON
	(PCS)	(PCS)	(PCS)
TUBE	80	4,000	32,000

 $_{\mathbf{\sigma}}$



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